

- BRS: 32 with 33
- Pending
- Active
- L1: (1) 10/718310
- L2: (6) 5519236, pn. "20020127803" "20020127796"
- L3: (1342) (semiconductor active) adj (strip \$4 web)
- L4: (17333) second adj2 well
- L5: (554) 257/302.CCLS.
- L6: (10) 4 and 5
- L7: (17854) first adj2 well
- L8: (73343) "same" near2 (conduct\$4 impurity dop\$4)
- L9: (4658) 4 with 7
- L10: (4819 with 8
- L11: (45548) (wordline "WL" (word near (read\$3 wrt\$3)))
- L12: (3216814) contact
- L13: (0) 10 with 11
- L14: (5090) deep adj trench
- L15: (715) buried adj strap
- L16: (180) 14 near9 15
- L17: (3149775) identical similar \$2
- L18: (5) (17 "same") with 16
- L19: (1) 09/607217
- L20: (20) 2.6.18
- Failed
- Saved
- (1) 09/948877
- (1) 7381 "KONINKLIJKE PUIJIPS"

Aug 2004

Browse Queue Clear

DBs: USPAT-US_PCTPLD_EPO-IPO-DIVERVENT-IBM_TDB Plurals Highlight all hit terms initially

Default operator: OR

2 6 18

U	I	Document	Issue	F100	Current	Correct	XRef	Retired	S	C	P	3	4	5	6	7	8	Image	Date	P
1	<input type="checkbox"/>	Bostelmann, U	US 6344390	20020.2	Methods of forming the buried strap and its g	438/249 257/E21.65			<input checked="" type="checkbox"/>	US 634439										
2	<input type="checkbox"/>	Kowalski, Be	US 2004010	20040.9	Transistor array and semiconductor memory	257/302			<input checked="" type="checkbox"/>	US 200401										
3	<input type="checkbox"/>	Losee, Becky	US 2002019	20020.1	Method for etching silicon trenches	438/709 257/302			<input checked="" type="checkbox"/>	US 200201										
4	<input checked="" type="checkbox"/>	Schlosser, Tim	US 200212	20020.1	Method for producing a memory cell for a se	438/258 257/E21.65			<input checked="" type="checkbox"/>	US 200201										
5	<input type="checkbox"/>	Hofmann, Fra	US 200212	20020.1	Method for producing a cell of a semiconduct	438/243 257/E21.65			<input checked="" type="checkbox"/>	US 200201										
6	<input type="checkbox"/>	Kim, Ho-Hyun	US 2002008	20020.1	MOS control diodes and method for manufac	257/135 257/242			<input checked="" type="checkbox"/>	US 200200										
7	<input type="checkbox"/>	Wu, Xiaojun et	US 2002007	20020.1	Electronic circuit with electrical hole isolat	257/302 257/E21.37			<input checked="" type="checkbox"/>	US 200200										
8	<input type="checkbox"/>	Hsu, Louis L.	US 2002007	20020.1	Structure and method for creating vertical c	257/302/257/E23.14			<input checked="" type="checkbox"/>	US 200200										
9	<input type="checkbox"/>	Schroeder, H	US 6747303	20040.1	CHARGE DETECTOR SEMICONDUCTOR CO	257/296 257/297			<input checked="" type="checkbox"/>	US 674730										
10	<input type="checkbox"/>	Seitz, Michael	US 8706634	20040.7	Control of separation between transfer gate	438/692 257/E21.65			<input checked="" type="checkbox"/>	US 870663										

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Ready

500M